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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/639,058	08/11/2003	Andrew E. Horch	2000.004.00/US	6760	
41894	7590 03/30/2005		EXAM	EXAMINER	
WALTER D. FIELDS			TRINH,	TRINH, HOA B	
FIELDS IP, PS 601 MAIN STREET			ART UNIT	PAPER NUMBER	
SUITE 405			2814		
VANCOUVER, WA 98660			DATE MAILED: 03/30/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
	10/639,058	HORCH, ANDREW E.				
Office Action Summary	Examiner	Art Unit				
	Vikki H. Trinh	2814				
The MAILING DATE of this communication apperiod for Reply	pears on the cover sheet with the co	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a rep If NO period for reply sepecified above, the maximum statutory period Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailinearned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a reply be tim ly within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from e, cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).				
Status						
1)⊠ Responsive to communication(s) filed on <u>07 J</u>	lanuary 2005.					
3) Since this application is in condition for allowa	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
4) ⊠ Claim(s) 1-101 is/are pending in the application 4a) Of the above claim(s) 20-101 is/are withdrest is/are allowed.  5) □ Claim(s) is/are allowed.  6) ⊠ Claim(s) 1-4 is/are rejected.  7) ⊠ Claim(s) 5-19 is/are objected to.  8) □ Claim(s) 1- v  are subject to restriction and/or	awn from consideration.					
Application Papers						
9)☐ The specification is objected to by the Examin	er.					
10)☐ The drawing(s) filed on is/are: a)☐ acc	I0) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.					
Applicant may not request that any objection to the	e drawing(s) be held in abeyance. See	37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the E	, , , , , , , , , , , , , , , , , , , ,	•				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Bureat * See the attached detailed Office action for a list	ts have been received.  ts have been received in Applicationity documents have been received in the control of	on No ed in this National Stage				
Attachment(s)						
1) Notice of References Cited (PTO-892)  4) Interview Summary (PTO-413)						
<ul> <li>2) Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date <u>0305</u>.</li> </ul>	Paper No(s)/Mail Da  5) Notice of Informal P  6) Other:	ate atent Application (PTO-152)				

# **DETAILED ACTION**

### Election/Restrictions

- 1. Claims 20-101 are withdrawn from further consideration pursuant to 37 CFR 1.142(b) as being drawn to a nonelected groups, there being no allowable generic or linking claim. Election was made without traverse in the reply filed on 01/07/05.
- 2. It is suggested that in response to this Office Action, applicant should cancel claims 20-101.

# Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-4 are rejected under 35 U.S.C. 102(b) as being anticipated by Chen et al. (hereinafter "Chen") "Fabrication of Self-Aligned 90-nm Fully Depleted SOI CMOS SLOTFETS".

Chen discloses, as to claim 1, method of fabricating a thyristor memory, comprising: forming sidewalls (fig. 1, steps (a) and (b)) in a layer of dielectric (fig. 1, step (a)) over a layer of semiconductor material (fig. 1, step (a)) to define a trench (fig. 1, step (a)) and expose a region (fig. 1, step (b)) of the semiconductor material through the opening of the trench; forming conductive material (fig. 1, step (c)) on at least portions of the dielectric and in the trench; patterning the conductive material to define first and second shoulders (fig. 1, step (d)) extending

outwardly from the trench over regions of the dielectric outside the trench; the patterning to comprise forming the first shoulder (fig. 1, step (d)) as an overhang extending laterally outward from the trench over regions of the layer of semiconductor material for the thyristor; etching exposed regions (fig. 1, step (e)) of the layer of dielectric to form an implant mask (fig. 1, step (d)) while using the conductive material with the first and second shoulders as an etch mask (fig. 1, step (d)), implanting regions (fig. 1, step (d)) of the layer of semiconductor material; and using the implant mask (fig. 1, step (e)) to align placement of dopant during at least a portion of the implanting.

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As to claim 2, the implanting comprises performing a first implant (col. 2, line 2) of first conductivity type dopant.

As to claim 3, the first implanting (fig. 1, step (d)) comprises penetrating with the dopant of the first conductivity type regions (col. 2, line 2) of the layer of semiconductor material beneath an edge of the implant mask.

As to claim 4, the first implanting (fig. 1, step (d)) comprises forming a base region to the thyristor; and forming at least a portion of the base region beneath the first shoulder (fig. 1).

# Allowable Subject Matter

- 3. Claims 5-19 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- 4. The following is an examiner's statement of reasons for allowance: The prior art of record does not disclose or fairly suggest either in singly or in combination a method of making a thyristor memory comprising the steps of etching exposed regions of the dielectric layer to form

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an implant mask while using the conductive material with the first and second shoulders as an etch mask; using the implant mask to align placement of dopant during at least a portion of the implanting; performing a second implant of the second conductivity type dopant aligned with the implant mask and forming an anode/cathode-emitter; and other steps in the claims.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

#### Conclusion

Any inquiry concerning this communication or earlier communications from the Examiner should be directed to Vikki Trinh whose telephone number is (571) 272-1719. The Examiner can normally be reached from Monday-Friday, 9:00 AM - 5:30 PM Eastern Time. If attempts to reach the examiner by telephone are unsuccessful, the Examiner's supervisor, Mr. Wael Fahmy, can be reached at (571) 272-1705. The office fax number is 703-872-9306.

Any request for information regarding to the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Also, status information for published applications may be obtained from either Private PAIR or Public Pair. In addition, status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <a href="http://pair-direct.uspto.gov">http://pair-direct.uspto.gov</a>. If you have questions pertaining to the Private PAIR system, please contact the Electronic Business Center (EBC) at 866-217-9197 (toll free).

Lastly, paper copies of cited U.S. patents and U.S. patent application publications will cease to be mailed to applicants with Office actions as of June 2004. Paper copies of foreign

patents and non-patent literature will continue to be included with office actions. These cited U.S. patents and patent application publications are available for download via the Office's PAIR. As an alternate source, all U.S. patents and patent application publications are available on the USPTO web site (www.uspto.gov), from the Office of Public Records and from commercial sources. Applicants are referred to the Electronic Business Center (EBC) at <a href="http://www.uspto.gov/ebc/index.html">http://www.uspto.gov/ebc/index.html</a> or 1-866-217-9197 for information on this policy. Requests to restart a period for response due to a missing U.S. patent or patent application publications will not be granted.

Vikki Trinh, Patent Examiner AU 2814

> HOWARD WEISS PRIMARY EXAMINER